Application/Control No. Applicant(s)/Patent Under Reexamination 09/955,632 PAREKH ET AL. Notic of References Cited Examiner Art Unit Page 1 of 1 Yennhu B Huynh 2813 U.S. PATENT DOCUMENTS Document Number Date Country Code-Number-Kind Code Name MM-YYYY Classification Χ US-5913129 Α 06-1999 Wu et al. 438/398 Χ В US-5418180 05-1995 Brown 438/396 С US-5324679 06-1994 Kim et al. 438/386 US-D US-Ε F US-G US-Н US-I US-J US-Κ US-US-Μ US-FOREIGN PATENT DOCUMENTS **Document Number** Date Country Country Code-Number-Kind Code Name Classification MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS**

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